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Welcome to the 25th International Test Conference, the premier technical conference on electronic testing. By joining us at ITC 94, you are participating in a week of activities aimed at your professional development and the development of the test profession.

Hundreds of ITC volunteers, staff, and presenters have created ITC Test Week, a week of activities including formal papers, panel discussions, exhibits, tutorials, test standard working meetings, and other professional society meetings. In response to last year's popularity, ITC again offers the Exhibitors Forum the day before the technical program. This forum provides a convenient snapshot of today's available test technology and helps to organize your visit to the Exhibit Floor.

ITC paper selection is highly competitive and these Proceedings include many of the finest test technology papers in the world. This year's conference celebrates twenty-five years of the annual test conference and looks forward with optimism to the next twenty-five. The plenary session provides a short look at prior conferences but the primary focus is to the future, in accordance with this year's theme: *Test: The Next Twenty-Five Years*. Several panel discussions also provide insight into industry and technology trends.

This year's conference introduces a new format that incorporates both leading-edge and mainstream subjects. One such leading-edge topic, *Test Synthesis*, features a new tutorial, panel discussion, and special day-long seminar. *Multi-chip module (MCM) Testing* is another emerging technology and the conference features two sessions, a panel discussion, and a tutorial on this important topic.

Boundary scan and *I_{DDQ}-related testing* continue to be popular as test technology evolves, but other topical areas are gaining in interest. *Mixed-Signal Testing* continues its

explosive growth in both variety and complexity of applications. *Systems Testing* is continuing its revolutionary change towards more structure, coordination of DFT tools at all system levels, and standardization.

ITC's traditional test topics are also well represented at ITC. There are sessions devoted to *ATPG*, *test equipment hardware*, *software testing*, *DFT*, *applied BIST*, *board testing*, *test economics*, *memory testing*, *test engineering*, and *test quality and reliability*. These sessions could provide that crucial spark of inspiration that leads to innovative solutions in your own work.

ITC Test Week offers an abundant variety of outstanding exhibits, technical papers, panel discussions, and tutorials. For example: A new digital test engineering tutorial has been developed to meet the needs of test professionals in the 90s. The popular ISO 9000 tutorial is again offered for ITC attendees at no extra cost. Many technical meetings held during Test Week provide numerous opportunities to learn, contribute, and form professional networks.

You will get the most from ITC by participating in as much as you can. Our social events in the historic Washington D.C. area offer the opportunity to add to your professional network and renew old acquaintances. Finally, please take time to fill out our survey so we can improve ITC to better meet your needs.

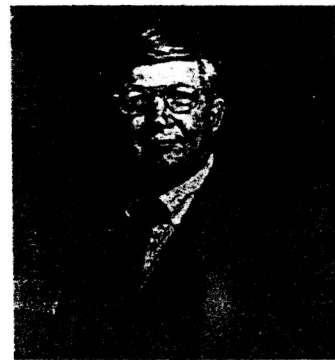
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Welcoming Message



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